

Notice of References Cited

Application/Control No.

10/517,623

Applicant(s)/Patent Under
Reexamination
YABE ET AL.

Examiner

HEE SOO KIM

Art Unit

2157

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,275,850 B1 | 08-2001 | Beyda et al. | 709/206 |
| * | B | US-2002/0016818 A1 | 02-2002 | Kirani et al. | 709/203 |
| * | C | US-2002/0138586 A1 | 09-2002 | Paleiov et al. | 709/207 |
| * | D | US-2004/0049696 A1 | 03-2004 | Baker et al. | 713/201 |
| * | E | US-2005/0124337 A9 | 06-2005 | Gresham et al. | 455/431 |
| * | F | US-7,117,246 B2 | 10-2006 | Christenson et al. | 709/206 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-------------------|----------------|
| * | N | JP 11272582 A | 10-1999 | Japan | KAWAMURA, TAKUSHI | G06F 13/00 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.